Amendments to the Claims

The claims have been amended as follows. <u>Underlines</u> indicate insertions and strikeouts Indicate deletions.



1. (Currently amended) A physical vapor deposition target comprising a material with a face centered cubic unit cell, having a sputtering surface, and formed by a process comprising:

casting;

aging; and

equal channel angular extrusion; and

after the equal channel angular extrusion, modifying crystallographic texture orientation by additional processing comprising at least one of cross-rolling and forging to enhance one of axial-oriented <220> and planar-oriented <220> crystallographic texture; the target having a predominate <220> crystallographic texture across the sputtering surface, and an average grain size across the sputtering surface of less than or equal to about 30 microns.

- 2. (Original) The physical vapor deposition target of claim 1 wherein the average grain size across the sputtering surface is less than or equal to 1 micron.
- 3. (Original) The physical vapor deposition target of claim 1 further comprising substantially no pores or voids proximate the sputtering surface.

- 4. (Original) The physical vapor deposition target of claim 1 wherein the predominate <220> crystallographic texture is a strong <220> crystallographic texture.
- 5. (Original) The physical vapor deposition target of claim 1 comprising a ratio of the <220> crystallographic orientation to all other orientations of the face centered cubic unit cell of at least about 80%.
- 6. (Original) The physical vapor deposition target of claim 1 comprising a ratio of the <220> crystallographic orientation to all other orientations of the face centered cubic unit cell of at least about 90%.
- 7. (Original) The physical vapor deposition target of claim 1 wherein substantially all of the grain sizes across the sputtering surface are less than about 30 microns.
- 8. (Original) The physical vapor deposition target of claim 1 wherein substantially all of the grain sizes across the sputtering surface are less than 1 micron.
- 9. (Currently amended) The physical vapor deposition target of claim 1 wherein the additional processing comprises forging and the <220> texture comprises predominately axial <220> orientations.



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- (Currently amended) Th physical/vapor deposition target of claim 1 wh rein 10. the additional processing comprises cross-rolling and the <220> texture comprises predominately planar <220> orientations.
- (Previously amended) The/physical vapor deposition target of claim 1 11. comprising at least one element selected/from the group consisting of aluminum, copper, silver, gold, nickel, brass, cerium, cobalt/calcium, iron, lead, palladium, platinum, rhodlum, strontium, ytterbium, and thorium.
- (Previously amended) The physical vapor deposition target of claim 1 12. comprising at least one element selected from the group consisting of aluminum, copper, gold, nickel, and platinum.
- (Original) The physical vapor deposition target of claim 1 wherein any 13. precipitates present in the target have a maximum dimension of 0.5 micron.

Claims 14-66. (Cancelled).



comprising:

67. (Currently amended) A physical vapor deposition target comprising a copper material with a face centered cubic unit cell, having a sputtering surface, and comprising: a predominate <220> crystallographic texture across the sputtering surface; and an average grain size across the sputtering surface of less than or equal to about 30 microns, wherein any second-phase precipitates present in the target have a maximum dimension of 0.5 micron, the material being formed by a process including casting

equal channel angular extrusion to produce a microstructure; and

aging to induce the second-phase precipitates for enhancing stability of the microstructure produced by the equal channel angular extrusion.

- 68. (Currently amended) The physical vapor deposition target of claim 67 further comprising at least one element selected from the group consisting of aluminum, silver, and gold.
- 69. (Previously added) The physical vapor deposition target of claim 68 comprising aluminum.
- 70. (Previously added) The physical vapor deposition target of claim 68 comprising silver.
- 71. (Previously added) The physical vapor deposition target of claim 68 comprising gold.



- 72. (Previously added) The physical vapor deposition target of claim 67 wherein the average grain size across the sputtering surface is less than or equal to 1 micron.
- 73. (Previously added) The physical vapor deposition target of claim 67 further comprising substantially no pores or voids proximate the sputtering surface.
- 74. (Previously added) The physical vapor deposition target of claim 67 wherein the predominate <220> crystallographic texture is a strong <220> crystallographic texture.
- 75. (Previously added) The physical vapor deposition target of claim 67 comprising a ratio of the <220> crystallographic orientation to all other orientations of the face centered cubic unit cell of at least/about 80%.
- 76. (Previously added) The physical vapor deposition target of claim 67 comprising a ratio of the <220> crystallographic orientation to all other orientations of the face centered cubic unit cell of at least about 90%.
- 77. (Previously added) The physical vapor deposition target of claim 67 wherein substantially all of the grain sizes across the sputtering surface are less than about 30 microns.



- 78. (Previously added) The physical vapor deposition target of claim 67 wherein substantially all of the grain sizes across the sputtering surface are less than 1 micron.
- 79. (Previously added) The physical vapor deposition target of claim 67 wherein the <220> texture comprises predominately axial <220> orientations.
- 80. (Previously added) The physical vapor deposition target of claim 67 wherein the <220> texture comprises predominately planar <220> orientations.

Claims 81-83 (Cancelled).

